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- 10KH Compatible
- Open-Collector Outputs Drive Bus Lines or Buffer Memory Address Registers
- ECL and TTL Output-Enable Inputs
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC}, V_{EE}, and GND Configurations Minimize High-Speed Switching Noise
- Package Options Include "Small Outline" Packages and Standard Plastic 300-mil DIPs

(TOP VIEW) Y1 [24 A1 Y2 **∏** 2 23 A2 Y3 **∏** 3 22 A3 Y4 **1** 4 21 A4 20 OE2 (TTL) V_{CC} [] 5 GND 6 19 V_{EE} GND **∏** 7 18 GND 17 OE1 (ECL) GND T 8 Y5 **1** 9 16 A5 Y6 **1** 10 15 A6 Y7 🛮 14 A7 11 Y8 **∏** 13**|** A8 12

DW OR NT PACKAGE

description

This octal ECL-to-TTL translator is designed to provide efficient translation between a 10KH signal environment and a TTL signal environment. This device is designed specifically to improve the performance and density of ECL-to-TTL CPU/bus-oriented functions such as memory-address drivers, clock drivers, and bus-oriented receivers and transmitters while eliminating the need for 3-state overlap protection.

Two pins $\overline{\text{OE}}1$ and $\overline{\text{OE}}2$ are provided for output-enable control. These control inputs are ANDed together with $\overline{\text{OE}}1$ being ECL-compatible and $\overline{\text{OE}}2$ being TTL-compatible. This offers the choice of controlling the outputs of the device from either a TTL or ECL signal environment.

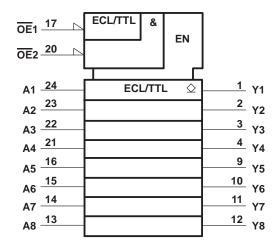
The SN10KHT5539 is characterized for operation from 0°C to 75°C.

FUNCTION TABLE

Γ	OUT	PUT	DATA	OUTPUT		
ı	ENA	BLE	INPUT	(TTL)		
	OE1	OE2	Α	Υ		
Γ	Χ	Н	Х	Н		
ı	Н	X	Х	Н		
ı	L	L	L	L		
	L	L	Н	Н		

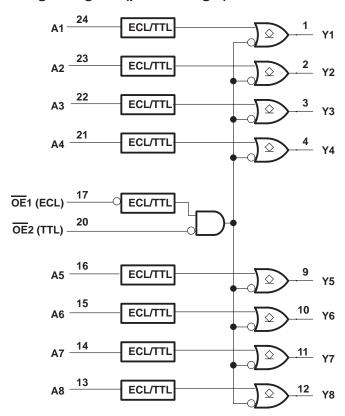
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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}	-0.5 V to 7 V
Supply voltage range, VEE	8 V to 0 V
Input voltage range: TTL (see Note 1)	$-1.2\ V$ to $7\ V$
ECL	V _{EE} to 0 V
Input current range, TTL	30 mA to 5 mA
Current into any output in the low state	96 mA
Voltage applied to any output in the high state	\dots -0.5 V to V _{CC}
Operating free-air temperature range	0°C to 75°C
Storage temperature range	65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The TTL input voltage ratings may be exceeded provided the input current ratings are observed.



recommended operating conditions

			MIN	NOM	MAX	UNIT
Vcc	TTL supply voltage			5	5.5	V
VEE	ECL supply voltage			-5.2	-5.46	V
VIH	TTL high-level input voltage					V
VIL	TTL low-level input voltage				0.8	V
		$T_A = 0$ °C	-1170		-840	mV
\vee_{IH}	ECL high-level input voltage†	T _A = 25°C	-1130		-810	
	$T_A = 75$	T _A = 75°C	-1070		-735	
		$T_A = 0$ °C	-1950		-1480	mV
\vee_{IL}	ECL low-level input voltage†	T _A = 25°C	-1950		-1480	
		T _A = 75°C	-1950		-1450	
Vон	TTL high-level output voltage				5.5	V
ΙK	TTL input clamp current				-18	mA
loL	Low-level output current				48	mA
TA	Operating free-air temperature range				75	°C

[†] The algebraic convention, in which the least positive (most negative) value is designated minimum, is used in this data sheet for logic levels only.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TER TEST CONDITIONS			MIN	TYP‡	MAX	UNIT	
٧IK	OE2 only	$V_{CC} = 4.5 \text{ V},$	$V_{EE} = -4.94 \text{ V},$	$I_{I} = -18 \text{ mA}$				-1.2	V
IOH		$V_{CC} = 4.5 \text{ V},$	$V_{EE} = -4.94 \text{ V},$	V _{OH} = 5.5 V				250	μΑ
VOL		$V_{CC} = 4.5 \text{ V},$	$V_{EE} = -5.2 \text{ V} \pm 5\%,$	$I_{OL} = 48 \text{ mA}$			0.38	0.55	V
lį	OE2 only	$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V},$	V _I = 7 V				0.1	mA
lΗ	OE2 only	$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V},$	$V_{I} = 2.7 \text{ V}$	V _I = 2.7 V			20	μΑ
Ι _Ι L	OE2 only	$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V},$	$V_{I} = 0.5 V$				-0.5	mA
	A inputs and OE1	$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V},$	$V_{I} = -840 \text{ mV}$	T _A = 0°C			350	μΑ
lН		$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V},$	$V_{I} = -810 \text{ mV}$	T _A = 25°C			350	
		$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V},$	$V_{I} = -735 \text{ mV}$	T _A = 75°C			350	
	A inputs and OE1	V _{CC} = 5.5 V,	$V_{EE} = -5.46 \text{ V},$	$V_{I} = -1950 \text{ mV}$	T _A = 0°C	0.5			
IIL					T _A = 25°C	0.5		μA	μΑ
					T _A = 75°C	0.5			
ICCH		$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V}$				63	91	mA
ICCL		$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V}$				79	114	mA
IEE		$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V}$	·			-22	-32	mA
Ci		$V_{CC} = 5 V$,	$V_{EE} = -5.2 \text{ V}$	·			6		pF
Co		$V_{CC} = 5 V$,	V _{EE} = −5.2 V				5		pF

 $[\]ddagger$ All typical values are at V_{CC} = 5 V, V_{EE} = -5.2 V, T_A = 25°C.



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switching characteristics over recommended ranges of operating supply voltage and free-air temperature (unless otherwise noted) (see Figure 1)

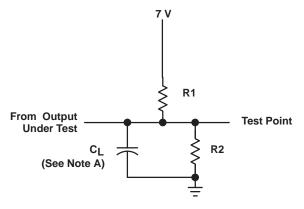
PARAMETER	FROM (INPUT)	TO (OUTPUT)	C_L = 50 pF, R1 = 500 Ω , R2 = 500 Ω			UNIT
			MIN	TYP [†]	MAX	
t _{PLH}			6.2	9.3	12.4	
t _{PHL}	Any A	Y	2.6	4.9	7.3	ns
tPLH	_		7.1	10.3	13.5	
t _{PHL}	OE1 (ECL)	Y	3.2	5.8	8.4	ns
t _{PLH}	OF (TTL)	V	6.5	9.5	12.4	
t _{PHL}	OE2 (TTL)	Y	2.7	5.3	8	ns

[†] All typical values are at V_{CC} = 5 V, V_{EE} = -5.2 V, T_A = 25°C.

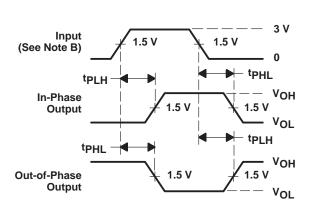


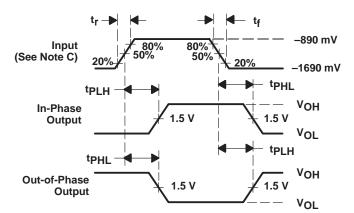
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PARAMETER MEASUREMENT INFORMATION



LOAD CIRCUIT





TTL-INPUT PROPAGATION DELAY TIMES

ECL-INPUT PROPAGATION DELAY TIMES

NOTES: A.C_L includes probe and jig capacitance.

- B. For TTL inputs, input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_0 = 50 \Omega$, $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- C. For ECL inputs, input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_0 = 50~\Omega$, $t_f \leq$ 1.5 ns, $t_f \leq$ 1.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. load circuit and voltage waveforms

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